

276 Abby Road, Manchester, NH 03103 USA Tel: 1+ 603.935.4100

Email: ARMI@lgcgroup.com | Online: ARMI.com

Certified Reference Material

Certificate of Analysis

ISO 17034:2016

ISO/IEC 17025:2017



Product ID: MBH-AL356.2-19

Product Description: Aluminum Alloy, AA356.2 / A03562

Description and Intended Use: This Certified Reference Material is covered under the scope of accreditation to ISO 17034 by LGC Standards - Manchester, NH. As an ISO 17034 certified reference material, appropriate use of this material will fulfill the certified reference material and traceability requirements for use in ISO 17025 accredited laboratories. This CRM may come in the form of a solid disk, or chips. The intended use of this CRM may include, but is not limited to, the calibration of instruments and the validation of analytical methods.

	Certified Values listed in wt.% with associated uncertainties														
Bi	0.0083	± 0.0007	Ca	0.0031	± 0.0007	Cd	0.0023	± 0.0004	Co	0.0008	± 0.0002				
Cr	0.030	± 0.001	Cu	0.172	± 0.009	Fe	0.22	± 0.01	Ga	0.015	± 0.002				
Mg	0.39	± 0.01	Mn	0.052	± 0.002	Ni	0.058	± 0.003	Pb	0.105	± 0.009				
Sb	0.0041	± 0.0005	Si	6.9	± 0.1	Sn	0.0076	± 0.0005	Sr	0.0168	± 0.0008				
Ti	0.185	± 0.004	٧	0.029	± 0.001	Zn	0.088	± 0.003	Zr	0.0057	± 0.0005				
					Indicative Val	ues liste	ed in ppm								

(<10) (<20)

Homogeneity and Uncertainty: "Uncertainty" values, as reported adjacent to certified concentration values, are based on a 95% Confidence Interval. These estimated uncertainties include the combined effects of method imprecision, material inhomogeneity, and any bias between methods. Homogeneity data from experimental XRF results are reflected in both the overall statistics and certified data. Homogeneity samples are selected by a systematic sampling procedure. The number of samples may be determined by equation 1, where N_{prod} is the number of units produced and N_{min} is the number of samples used for homogeneity testing. These samples are arranged in a simple randomized design such that each sample is analyzed multiple times by XRF. Homogeneity may also be determined within sample using an applied version of ASTM E826. A single factor ANOVA is used to calculated uncertainty due to inhomogeneity (U_{hom}). Uncertainty of the material is calculated by eguation 2, where H=U_{hom}, S= Standard deviation, t= t-value at 95% CI, and n= number of observations.

1.
$$N_{MIN} = \max(10, \sqrt[3]{N_{PROD}})$$
 2. $U_{CRM} = \frac{\sqrt{H^2 + S^2}}{\sqrt{n}} * t$

Certification Laboratories: Much of the analytical work performed to assess this material has been carried out by laboratories with proven competence, as indicated by their accreditation to ISO 17025. It is an implicit requirement for this accreditation that analytical work should be performed with due traceability, via an unbroken chain of comparisons, each with stated uncertainty, to primary standards such as the mole, or to nationally- or internationally-recognised reference materials. Of the individual results herein, some have traceability (to the mole) via primary analytical methods. Some are traceable to substances of known stoichiometry. Most have traceability via commercial solutions. Furthermore, some results have additional traceability to NIST standards, as part of the analytical calibration or process control.

- LGC Standards Manchester, NH
- RSML Bengaluru, India
- NSL Analytical Services Cleveland, OH
- Laboratory Testing, Inc. Hatfield, PA
- Connecticut Metallurgical, Inc. East Hartford, CT
- IMR Test Labs Lansing NY
- SGS MSi Melrose Park, IL
- Scrooby's Laboratory Service Rynfield, South Africa
- Applied Technical Services Marietta, GA
- FAG Laboratories Liverpool NY
- AnchorCert Analytical Birmingham, UK
- Luvak Inc. Boviston, MA

Instructions for Use: The test surface is on the opposite side of the labeled surface, which includes the material identification. The entire thickness of the unit is certified. However, the user is cautioned not to measure disks less than 2 mm thick when using X-ray fluorescence spectrometry. Each packaged disk has been prepared by finishing the test surface using a lathe. The user must determine the correct surface preparation procedure for each analytical technique. The user is cautioned to use care when either resurfacing the disk or performing additional polishing, as these processes may contaminate the surface. The minimum sample size for chips should be individually evaluated based on the analytical technique used; this would typically be greater than 0.1 grams. The material should be stored in a cool, dry location when not in use. Chips are not recommended for gas analysis.

Period of Validity: The certification of this material is valid indefinitely, within the uncertainty specified, provided the material is handled and stored in accordance with the instructions stated on this certificate. The certification is nullified if the material is damaged, contaminated, otherwise modified, or used in a manner for which it was not intended.

October 7, 2021



ISO 17034 Accredited: Reference Materials Producer Certificate # 2848 02 ISO/IEC 17025 Accredited: Chemical Testing, Certificate # 2848.01



The following data represents all pertinent information reported as it applies to the chemical characterization of this material.

	Ag	Al	В	Be	Bi	Ca	Cd	Co	Cr	Cu	Fe	Ga	Li	Mg
1	0.00002	88.800	0.0005	0.0001	0.0074	0.0023	0.0015	0.0004	0.0260	0.1347	0.1916	0.0094	0.0001	0.3600
2	0.0004	91.800	0.0008	0.0002	0.0075	0.0023	0.0016	0.0005	0.0260	0.1420	0.1950	0.0120	0.0001	0.3720
3	<0.0001	91.810	0.0010	0.0002	0.0075	0.0025	0.0019	0.0005	0.0286	0.1570	0.2000	0.0130	0.0010	0.3790
4	<0.0005	91.828	<0.0001	0.0003	0.0076	0.0030	0.0020	0.0005	0.0290	0.1580	0.2078	0.0130	<0.0001	0.3840
5	< 0.001	92.020	<0.0001	<0.0001	0.0080	0.0035	0.0020	0.0008	0.0290	0.1710	0.2207	0.0138	<0.0005	0.3874
6	<0.001	94.760	<0.001	<0.0005	0.0080	0.0039	0.0026	0.0009	0.0291	0.1750	0.2210	0.0142	<0.001	0.3880
7				<0.001	0.0081	0.0043	0.0026	0.0010	0.0295	0.1760	0.2230	0.0149		0.3905
8				<0.001	0.0088	<0.02	0.0026	0.0011	0.0297	0.1770	0.2260	0.0151		0.3920
9					0.0089		0.0027	0.0012	0.0300	0.1780	0.2270	0.0152		0.3929
10					0.0090		0.0029	<0.0005	0.0300	0.1806	0.2337	0.0171		0.3960
11					0.0105		0.0030	<0.001	0.0303	0.1808	0.2370	0.0173		0.4067
12								<0.001	0.0308	0.1818	0.2371	0.0180		0.4090
13									0.0314	0.1843	0.2389	0.0199		0.4130
14									0.0337	0.1870	0.2420			0.4270
15										0.1922				
16														
17														
18														
19														
20														
21														
Mean	0.0002	91.836	0.0008	0.0002	0.0083	0.0031	0.0023	0.0008	0.0295	0.1717	0.2215	0.0148	0.0004	0.3927
STDV	0.0003	1.8870	0.0003	0.0001	0.0009	0.0008	0.0005	0.0003	0.0020	0.0165	0.0168	0.0028	0.0005	0.0173
Certified	(<0.001)	(92)	(<0.0008)	(0.0002)	0.0083	0.0031	0.0023	0.0008	0.030	0.172	0.22	0.015	(<0.001)	0.39
U _{CRM}					0.0007	0.0007	0.0004	0.0002	0.001	0.009	0.01	0.002		0.01
Methods	O,IM,I	0,1	O,IM,I	O,IM,I	O,I,IM	0,1	O,I,IM	O,I,IM	O,I,IM,X	O,I,IM,X	O,I,IM,X	O,IM,I,X	O,IM,I	O,I,IM,X

	Mn	Ni	P	Pb	S	Sb	Si	Sn	Sr	Ti	V	Zn	Zr	
1	0.0450	0.0480	0.0012	0.0800	0.0015	0.0030	6.7750	0.0060	0.0139	0.1750	0.0264	0.0770	0.0050	
2	0.0480	0.0520	0.0012	0.0826	0.0020	0.0034	6.8280	0.0064	0.0163	0.1761	0.0269	0.0789	0.0050	
3	0.0490	0.0530	0.0097	0.0850	<0.0001	0.0039	6.8560	0.0070	0.0166	0.1800	0.0272	0.0830	0.0051	
4	0.0490	0.0534	<0.0001	0.0910	<0.0005	0.0040	6.8700	0.0070	0.0169	0.1809	0.0278	0.0850	0.0053	
5	0.0495	0.0540	<0.002	0.0960		0.0040	6.8840	0.0075	0.0170	0.1810	0.0280	0.0860	0.0053	
6	0.0505	0.0560	<0.002	0.1000		0.0042	6.9029	0.0076	0.0170	0.1820	0.0284	0.0864	0.0054	
7	0.0510	0.0589	< 0.005	0.1023		0.0042	6.9311	0.0078	0.0172	0.1830	0.0287	0.0877	0.0060	
8	0.0526	0.0618		0.1028		0.0046	6.9400	0.0078	0.0174	0.1850	0.0296	0.0880	0.0064	
9	0.0530	0.0620		0.1060		0.0050	6.9400	0.0080	0.0174	0.1881	0.0300	0.0890	0.0064	
10	0.0530	0.0621		0.1100		0.0050	7.0750	0.0081	0.0180	0.1890	0.0316	0.0896	0.0068	
11	0.0533	0.0636		0.1154				0.0082	<0.01	0.1900	0.0318	0.0920		
12	0.0534	0.0640		0.1200				0.0084		0.1915	0.0320	0.0940		
13	0.0538	0.0649		0.1200				0.0090		0.1940	0.0337	0.0952		
14	0.0563	0.0650		0.1251						0.1953		0.0953		
15	0.0563			0.1345								0.0956		
16														
17														
18														
19														
20														
21														
Mean	0.0516	0.0585	0.0040	0.1047	0.0018	0.0041	6.9002	0.0076	0.0168	0.1851	0.0294	0.0882	0.0057	
STDV	0.0031	0.0056	0.0049	0.0163	0.0004	0.0006	0.0808	0.0008	0.0011	0.0064	0.0023	0.0057	0.0007	
Certified	0.052	0.058	(<0.005)	0.105	(<0.002)	0.0041	6.9	0.0076	0.0168	0.185	0.029	0.088	0.0057	
UCRM	0.002	0.003		0.009		0.0005	0.1	0.0005	0.0008	0.004	0.001	0.003	0.0005	
Methods	O,I,IM,X	O,I,IM,X	O,IM,I	O,I,IM,X	O,C	O,IM,X,I	0,1	O,I,IM,X	O,IM,I,X	O,I,IM,X	O,I,IM,X	O,I,IM,X	O,IM,I,X	

Legend: W = Classical, C = Combustion, F = Fusion, A = AA or GFAA, I = ICP or DCP, IM=ICP-MS, D = DC Arc, O = AES, X = XRF, G = GDAES or GDMS, H = Hollow Cathode AES

